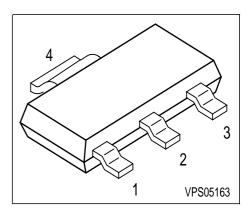


BCP68

NPN Silicon AF Transistor

- For general AF applications
- High collector current
- High current gain
- Low collector-emitter saturation voltage
- Complementary type: BCP69 (PNP)



Туре	Marking	Pin Configuration				Package
BCP68	BCP 68	1 = B	2 = C	3 = E	4 = C	SOT223
BCP68-25	BCP 68-25	1 = B	2 = C	3 = E	4 = C	SOT223

Maximum Ratings

Parameter	Symbol	Values	Unit	
Collector-emitter voltage	V _{CEO}	20	V	
Collector-emitter voltage	V _{CES}	25		
Collector-base voltage	V _{CBO}	25		
Emitter-base voltage	V _{EBO}	5		
DC collector current	I _C	1	A	
Peak collector current	I _{CM}	2		
Base current	I _B	100	mA	
Peak base current	/ _{BM}	200		
Total power dissipation, $T_{\rm S}$ = 124 °C	P _{tot}	1.5	W	
Junction temperature	Ti	150	°C	
Storage temperature	T _{stg}	-65 150		

Thermal Resistance

Junction - soldering point ¹⁾	R _{thJS}	≤17	K/W
	1155		

¹For calculation of R_{thJA} please refer to Application Note Thermal Resistance



Electrical Characteristics at $T_A = 25^{\circ}$ C, unless otherwise specified.

Parameter		Symbol	Values			Unit
			min.	typ.	max.	1
Characteristics		· · · · · · · · · · · · · · · · · · ·		•	•	
Collector-emitter breakdown vol	tage	V _{(BR)CEO}	20	-	-	V
<i>I</i> _C = 30 mA, <i>I</i> _B = 0						
Collector-emitter breakdown vol	tage	V _{(BR)CES}	25	-	-	
<i>I</i> _C = 10 μA, <i>V</i> _{BE} = 0						
Collector-base breakdown voltag	ge	V _{(BR)CBO}	25	-	-	
<i>I</i> _C = 10 μA, <i>I</i> _E = 0						
Emitter-base breakdown voltage	è	V _{(BR)EBO}	5	-	-	
<i>I</i> _E = 10 μA, <i>I</i> _C = 0		-				
Collector cutoff current		I _{CBO}	-	-	100	nA
V _{CB} = 25 V, <i>I</i> _E = 0						
Collector cutoff current		I _{CBO}	-	-	100	μA
$V_{\rm CB} = 25 \text{ V}, I_{\rm E} = 0 , T_{\rm A} = 150 \text{ °C}$;					
DC current gain 1)		h _{FE}	50	-	-	-
<i>I</i> _C = 5 mA, <i>V</i> _{CE} = 10 V						
DC current gain 1)		h _{FE}				
$I_{\rm C}$ = 500 mA, $V_{\rm CE}$ = 1 V	BCP68		85	-	375	
	BCP68-25		160	250	375	
DC current gain 1)		h _{FE}	60	-	-	
<i>I</i> _C = 1 A, <i>V</i> _{CE} = 1 V						
Collector-emitter saturation voltage1)		V _{CEsat}	-	-	0.5	V
<i>I</i> _C = 1 A, <i>I</i> _B = 100 mA						
Base-emitter voltage 1)		V _{BE(ON)}				
<i>I</i> _C = 5 mA, <i>V</i> _{CE} = 10 V			-	0.6	-	
<i>I</i> _C = 1 A, <i>V</i> _{CE} = 1			-	-	1	

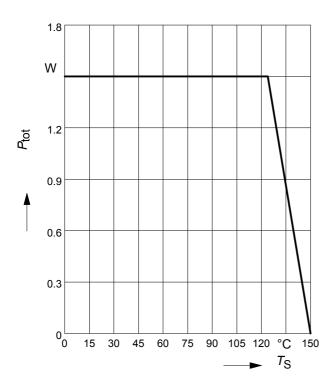
AC Characteristics

Transition frequency	f _T	-	100	-	MHz
/ _C = 100 mA, V _{CE} = 5 V, <i>f</i> = 100 MHz					

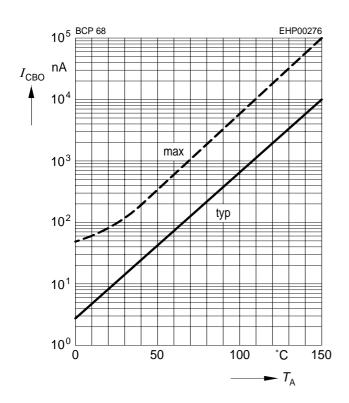
1) Pulse test: $t \le 300 \mu s$, D = 2%



Total power dissipation $P_{tot} = f(T_S)$

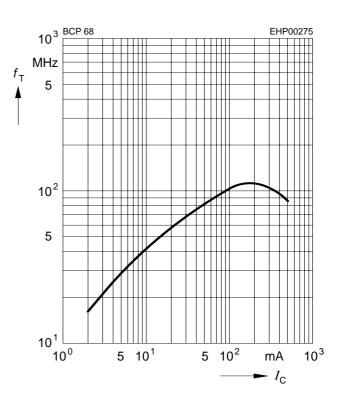


Collector cutoff current $I_{CBO} = f(T_A)$ $V_{CB} = 25V$

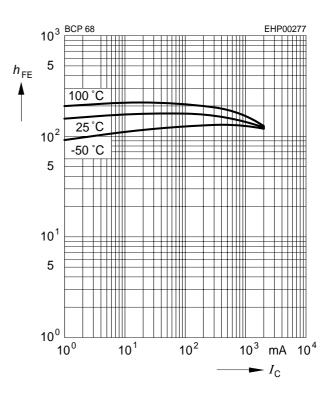


Transition frequency $f_{\rm T} = f(I_{\rm C})$

 $V_{CE} = 5V$



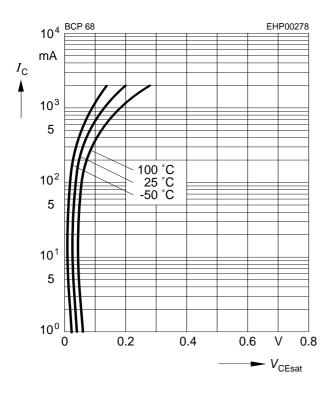
DC current gain $h_{\text{FE}} = f(I_{\text{C}})$ $V_{\text{CE}} = 1\text{V}$





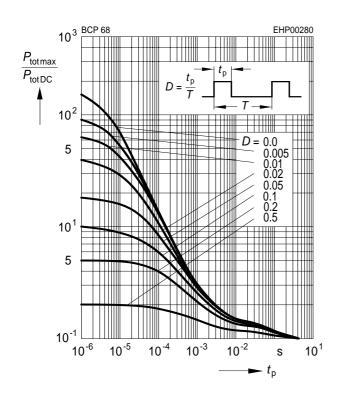
Collector-emitter saturation voltage

 $I_{\rm C} = f(V_{\rm CEsat}), h_{\rm FE} = 10$



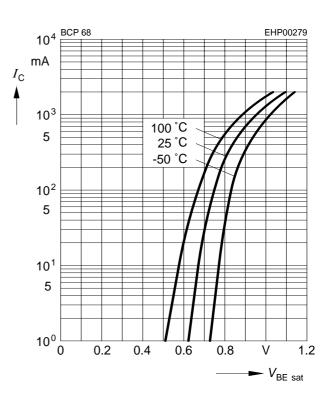
Permissible pulse load

 $P_{\text{totmax}} / P_{\text{totDC}} = f(t_p)$

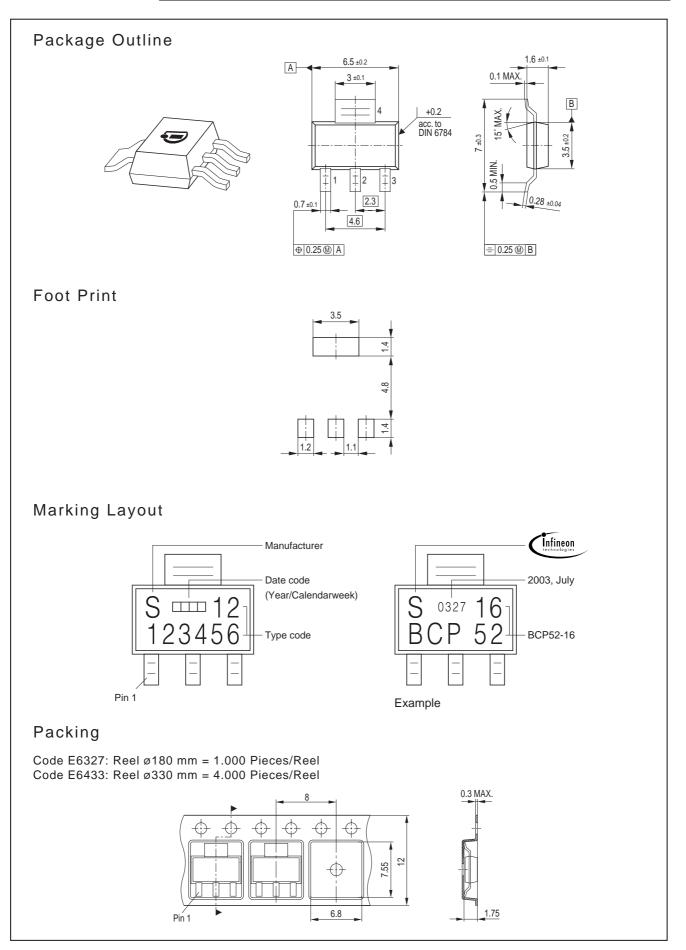


Base-emitter saturation voltage

 $I_{\rm C} = f(V_{\rm BEsat}), h_{\rm FE} = 10$









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